NL17SG17

Schmitt Buffer

The NL17SG17 MiniGate™ is an advanced high−speed CMOS Schmitt Buffer in ultra−small footprint.

The NL17SG17 input structures provides protection when voltages up to 4.6 V are applied.

Features

- Wide Operating V_{CC} Range: 0.9 V to 3.6 V
- High Speed: t_{PD} = 3.7 ns (Typ) at V_{CC} = 3.0 V, C_L = 15 pF
- Low Power Dissipation: I_{CC} = 0.5 μA (Max) at T_A = 25°C
- 4.6 V Overvoltage Tolerant (OVT) Input Pins
- Ultra−Small Packages
- These are Pb−Free and Halide−Free Devices

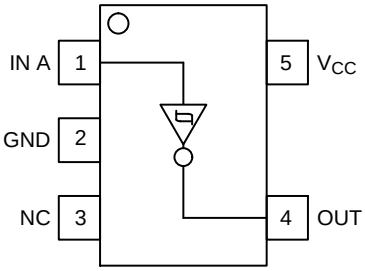


Figure 1. SOT−953
(Top Thru View)

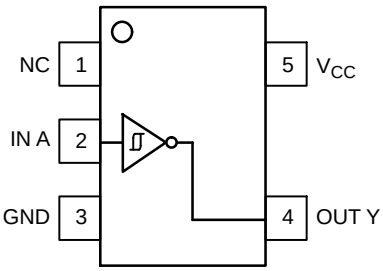


Figure 2. SC−88A
(Top View)

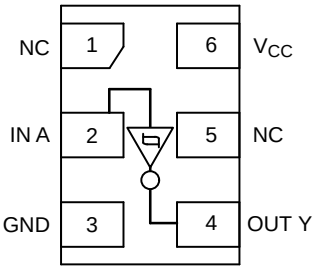


Figure 3. UDFN6
(Top View)

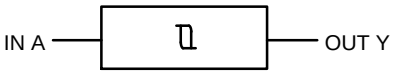


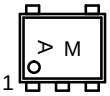
Figure 4. Logic Symbol

ON Semiconductor®

www.onsemi.com

MARKING DIAGRAMS

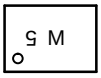
SOT−953
CASE 527AE



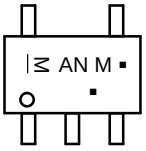
A = Specific Device Code
(A with 90 degree clockwise rotation)

UDFN6
1.0 x 1.0
CASE 517BX

UDFN6
1.45 x 1.0
CASE 517AQ



SC−88A
DF SUFFIX
CASE 419A



M = Date Code*
▪ = Pb−Free Package

(Note: Microdot may be in either location)

*Date Code orientation and/or position may vary depending upon manufacturing location.

PIN ASSIGNMENT

	SOT−953	SC−88A	UDFN6
1	IN A	NC	NC
2	GND	IN A	IN A
3	NC	GND	GND
4	OUT Y	OUT Y	OUT Y
5	V_{CC}	V_{CC}	NC
6			V_{CC}

FUNCTION TABLE

A Input	Y Output
L	L
H	H

ORDERING INFORMATION

See detailed ordering and shipping information on page 5 of this data sheet.

MAXIMUM RATINGS

Symbol	Parameter		Value	Unit
V_{CC}	DC Supply Voltage		−0.5 to +5.5	V
V_{IN}	DC Input Voltage		−0.5 to +4.6	V
V_{OUT}	DC Output Voltage	Output at High or Low State Power−Down Mode (V_{CC} = 0 V)	−0.5 to V_{CC} + 0.5 −0.5 to +4.6	V
I_{IK}	DC Input Diode Current	V_{IN} < GND	−20	mA
I_{OK}	DC Output Diode Current	V_{OUT} < GND	−20	mA
I_{OUT}	DC Output Source/Sink Current		±20	mA
I_{CC}	DC Supply Current per Supply Pin		±20	mA
I_{GND}	DC Ground Current per Ground Pin		±20	mA
T_{STG}	Storage Temperature Range		−65 to +150	°C
T_L	Lead Temperature, 1 mm from Case for 10 Seconds		260	°C
T_J	Junction Temperature Under Bias		+150	°C
MSL	Moisture Sensitivity		Level 1	
F_R	Flammability Rating	Oxygen Index: 28 to 34	UL 94 V−0 @ 0.125 in	
V_{ESD}	ESD Withstand Voltage	Human Body Model (Note 2) Machine Model (Note 3)	>2000 >100	V

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Measured with minimum pad spacing on an FR4 board, using 10 mm−by−1 inch, 2−ounce copper trace with no air flow.
2. Tested to EIA/JESD22−A114−A.
3. Tested to EIA/JESD22−A115−A.
4. Tested to EIA/JESD78.

RECOMMENDED OPERATING CONDITIONS

Symbol	Characteristics		Min	Max	Unit
V_{CC}	Positive DC Supply Voltage		0.9	3.6	V
V_{IN}	Digital Input Voltage		0.0	3.6	V
V_{OUT}	Output Voltage	Output at High or Low State Power−Down Mode (V_{CC} = 0 V)	0.0 0.0	V_{CC} 3.6	V
T_A	Operating Temperature Range		−55	+125	°C
$\Delta t / \Delta V$	Input Transition Rise or Fail Rate		0	No Limit	ns/V

Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability.

DC ELECTRICAL CHARACTERISTICS

Symbol	Parameter	Condition		V_{CC} (V)	T_A = 25°C			−55°C ≤ T_A ≤ 125°C		Unit
					Min	Typ	Max	Min	Max	
V_{T+}	Positive−Going Input Threshold Voltage			0.9		0.7	0.86		0.87	V
				1.1		0.81	0.95		1	
				1.4		0.94	1.16		1.2	
				1.65		1.06	1.25		1.3	
				2.3		1.36	1.6		1.65	
				3.0		1.8	2.05		2.1	
V_{T-}	Negative−Going Input Threshold Voltage			0.9	0.09	0.23		0.08		V
				1.1	0.15	0.33		0.12		
				1.4	0.3	0.47		0.25		
				1.65	0.35	0.6		0.3		
				2.3	0.55	0.85		0.5		
				3.0	0.95	1.13		0.9		
V_H	Hysteresis Voltage			0.9	0.15	0.5	0.75	0.2	0.8	V
				1.1	0.15	0.5	0.75	0.2	0.8	
				1.4	0.15	0.5	0.75	0.2	0.8	
				1.65	0.15	0.5	0.75	0.2	0.8	
				2.3	0.15	0.5	0.75	0.2	0.8	
				3.0	0.25	0.65	0.85	0.3	0.9	
V_{OH}	High−Level Output Voltage	V_{IN} = V_{IH} or V_{IL}	I_{OH} = −20 μA	0.9	0.75			0.75		V
			I_{OH} = −0.3 mA	1.1 to 1.3	0.75 x V_{CC}			0.75 x V_{CC}		
			I_{OH} = −1.7 mA	1.4 to 1.6	0.75 x V_{CC}			0.75 x V_{CC}		
			I_{OH} = −3.0 mA	1.65 to 1.95	V_{CC} − 0.45			V_{CC} − 0.45		
			I_{OH} = −4.0 mA	2.3 to 2.7	2.0			2.0		
			I_{OH} = −8.0 mA	3.0 to 3.6	2.48			2.48		
V_{OL}	Low−Level Output Voltage	V_{IN} = V_{IH} or V_{IL}	I_{OL} = 20 μA	0.9			0.1		0.1	V
			I_{OL} = 0.3 mA	1.1 to 1.3			0.25 x V_{CC}		0.25 x V_{CC}	
			I_{OL} = 1.7 mA	1.4 to 1.6			0.25xV_{CC}		0.25 x V_{CC}	
			I_{OL} = 3.0 mA	1.65 to 1.95			0.45		0.45	
			I_{OL} = 4.0 mA	2.3 to 2.7			0.4		0.4	
			I_{OL} = 8.0 mA	3.0 to 3.6			0.4		0.4	
I_{IN}	Input Leakage Current	0 ≤ V_{IN} ≤ 3.6 V		0 to 3.6			±0.1		±1.0	μA
I_{CC}	Quiescent Supply Current	V_{IN} = V_{CC} or GND		3.6			0.5		10.0	μA

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

AC ELECTRICAL CHARACTERISTICS (Input $t_r = t_f = 3.0$ ns)

Symbol	Parameter	Test Condition	V_{CC} (V)	T_A = 25 °C			T_A = −55°C to +125°C		Unit
				Min	Typ	Max	Min	Max	
t_{PLH}, t_{PHL}	Propagation Delay, A to Y	C_L = 10 pF, R_L = 1 MΩ	0.9	−	27.3	−	−	−	ns
			1.1 to 1.3	−	13.0	22.6	1.0	35.9	
			1.4 to 1.6	−	7.5	10.5	1.0	11.3	
			1.65 to 1.95	−	6.0	7.8	1.0	8.2	
			2.3 to 2.7	−	4.3	5.4	1.0	5.8	
			3.0 to 3.6	−	3.5	4.4	1.0	4.6	
		C_L = 15 pF, R_L = 1 MΩ	0.9	−	29.5	−	−	−	ns
			1.1 to 1.3	−	14.3	25.1	1.0	41.8	
			1.4 to 1.6	−	8.0	11.5	1.0	12.6	
			1.65 to 1.95	−	6.3	8.4	1.0	8.7	
			2.3 to 2.7	−	4.6	5.7	1.0	6.1	
			3.0 to 3.6	−	3.7	4.6	1.0	5.0	
		C_L = 30 pF, R_L = 1 MΩ	0.9	−	40.5	−	−	−	ns
			1.1 to 1.3	−	19.6	35.7	1.0	58.1	
			1.4 to 1.6	−	10.7	15.8	1.0	17.6	
			1.65 to 1.95	−	7.8	10.7	1.0	11.7	
			2.3 to 2.7	−	5.4	6.9	1.0	8.1	
			3.0 to 3.6	−	4.3	5.2	1.0	6.1	
C_{IN}	Input Capacitance		0 to 3.6		3	−	−	−	pF
C_O	Output Capacitance	V_O = GND	0		3	−	−	−	pF
C_{PD}	Power Dissipation Capacitance (Note 5)	f = 10 MHz	0.9 to 3.6	−	4	−	−	−	pF

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

5. C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the dynamic operating current consumption without load. Average operating current can be obtained by the equation: $I_{CC(OPR)} = C_{PD} \bullet V_{CC} \bullet f_{in} + I_{CC}$. C_{PD} is used to determine the no−load dynamic power consumption; $P_D = C_{PD} \bullet V_{CC}^2 \bullet f_{in} + I_{CC} \bullet V_{CC}$.

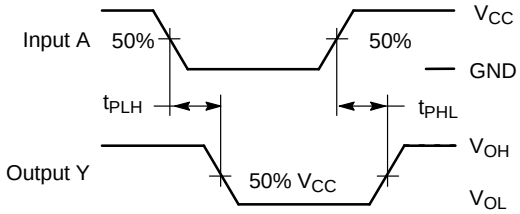
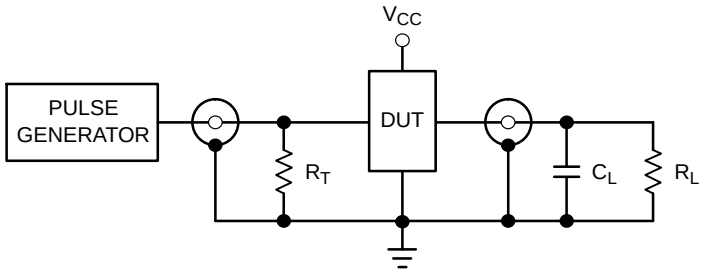


Figure 5. Switching Waveform



$R_T = Z_{OUT}$ of pulse generator (typically 50 Ω)

Figure 6. Test Circuit

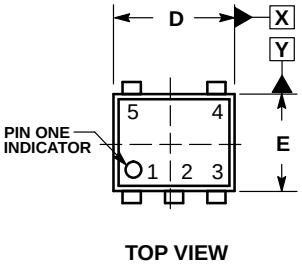
ORDERING INFORMATION

Device	Package	Shipping†
NL17SG17P5T5G	SOT−953 (Pb−Free)	8000 / Tape & Reel
NL17SG17DFT2G	SC−88A (Pb−Free)	3000 / Tape & Reel
NL17SG17AMUTCG*	UDFN6 1.45x1 mm (Pb−Free)	3000 / Tape & Reel
NL17SG17CMUTCG*	UDFN6 1x1 mm (Pb−Free)	3000 / Tape & Reel

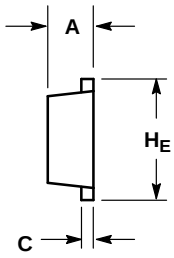
†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.
*In Development

PACKAGE DIMENSIONS

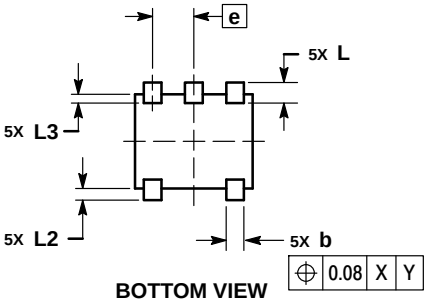
SOT−953
CASE 527AE
ISSUE E



TOP VIEW



SIDE VIEW

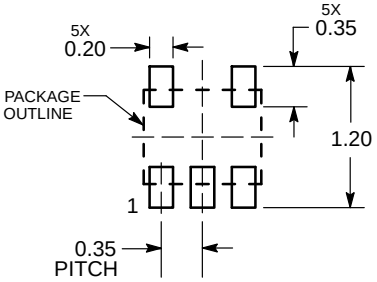


BOTTOM VIEW

NOTES:
1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
2. CONTROLLING DIMENSION: MILLIMETERS
3. MAXIMUM LEAD THICKNESS INCLUDES LEAD FINISH. MINIMUM LEAD THICKNESS IS THE MINIMUM THICKNESS OF THE BASE MATERIAL.
4. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.

	MILLIMETERS		
DIM	MIN	NOM	MAX
A	0.34	0.37	0.40
b	0.10	0.15	0.20
C	0.07	0.12	0.17
D	0.95	1.00	1.05
E	0.75	0.80	0.85
e	0.35 BSC		
HE	0.95	1.00	1.05
L	0.175 REF		
L2	0.05	0.10	0.15
L3	−−−	−−−	0.15

SOLDERING FOOTPRINT*

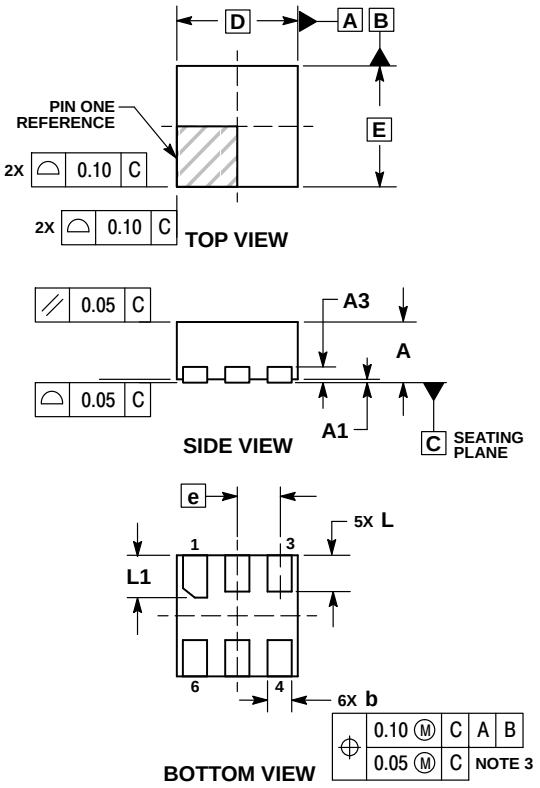


DIMENSIONS: MILLIMETERS

*For additional information on our Pb−Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

PACKAGE DIMENSIONS

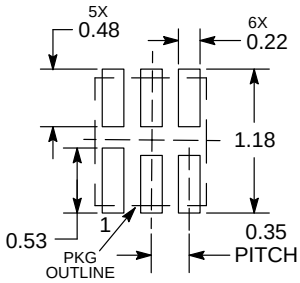
UDFN6 1.0x1.0, 0.35P
CASE 517BX
ISSUE O



NOTES:
1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
2. CONTROLLING DIMENSION: MILLIMETERS.
3. DIMENSION b APPLIES TO PLATED TERMINAL AND IS MEASURED BETWEEN 0.15 AND 0.20 MM FROM TERMINAL TIP.
4. PACKAGE DIMENSIONS EXCLUSIVE OF BURRS AND MOLD FLASH.

	MILLIMETERS	
DIM	MIN	MAX
A	0.45	0.55
A1	0.00	0.05
A3	0.13 REF	
b	0.12	0.22
D	1.00 BSC	
E	1.00 BSC	
e	0.35 BSC	
L	0.25	0.35
L1	0.30	0.40

RECOMMENDED SOLDERING FOOTPRINT*

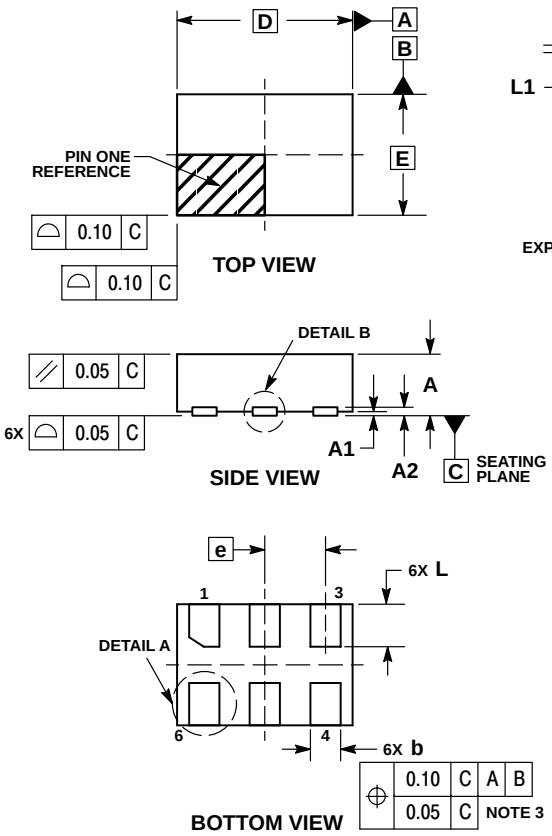


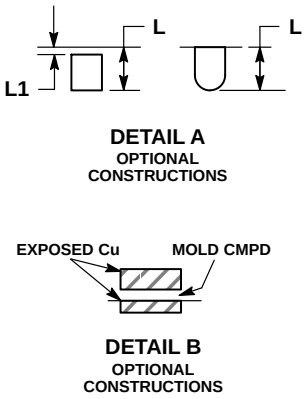
DIMENSIONS: MILLIMETERS

*For additional information on our Pb−Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

PACKAGE DIMENSIONS

UDFN6 1.45x1.0, 0.5P
CASE 517AQ
ISSUE O

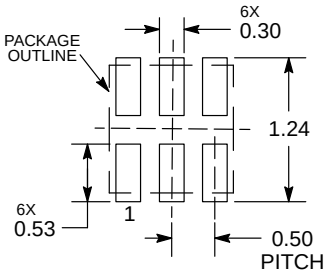




NOTES:
1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
2. CONTROLLING DIMENSION: MILLIMETERS.
3. DIMENSION b APPLIES TO PLATED TERMINAL AND IS MEASURED BETWEEN 0.15 AND 0.30 mm FROM THE TERMINAL TIP.

	MILLIMETERS	
DIM	MIN	MAX
A	0.45	0.55
A1	0.00	0.05
A2	0.07 REF	
b	0.20	0.30
D	1.45 BSC	
E	1.00 BSC	
e	0.50 BSC	
L	0.30	0.40
L1	−−−	0.15

MOUNTING FOOTPRINT

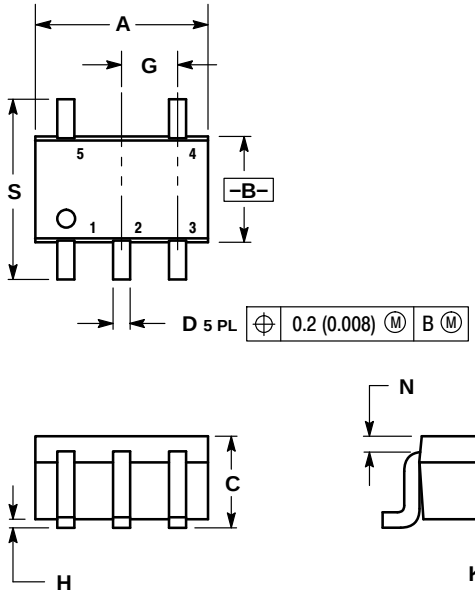


DIMENSIONS: MILLIMETERS

*For additional information on our Pb−Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

PACKAGE DIMENSIONS

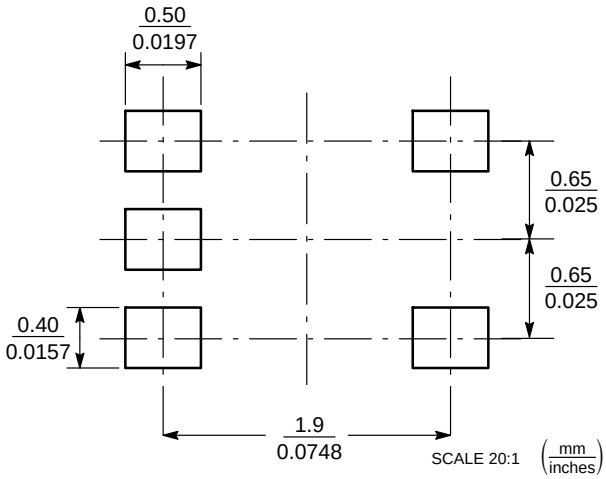
SC−88A (SC−70−5/SOT−353)
CASE 419A−02
ISSUE L



NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: INCH.
3. 419A−01 OBSOLETE. NEW STANDARD 419A−02.
4. DIMENSIONS A AND B DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.

	INCHES		MILLIMETERS	
DIM	MIN	MAX	MIN	MAX
A	0.071	0.087	1.80	2.20
B	0.045	0.053	1.15	1.35
C	0.031	0.043	0.80	1.10
D	0.004	0.012	0.10	0.30
G	0.026 BSC		0.65 BSC	
H	---	0.004	---	0.10
J	0.004	0.010	0.10	0.25
K	0.004	0.012	0.10	0.30
N	0.008 REF		0.20 REF	
S	0.079	0.087	2.00	2.20

SOLDER FOOTPRINT*



*For additional information on our Pb−Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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Email: orderlit@onsemi.com

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